



Application note
APN221_26_MHz_Crystal_specification

Department:		WTBU - Cellular Systems	
Creation Date:		2007-04-11	
Last Modified:		2007-07-30 by a0389010	
ID:		Version:	007
Status:	Approved	Approved By:	a0794494
EU ECCN:	5E002	US ECCN:	5E002

0 Document Control

© 2007 Texas Instruments Incorporated. All rights reserved.

Texas Instruments Incorporated and / or its subsidiaries (TI) reserve the right to make corrections, modifications, enhancements, improvements, and other changes to its products, software and services at any time and to discontinue any product, software or service without notice. Customers should obtain the latest relevant information during product design and before placing orders and should verify that such information is current and complete.

All products are sold subject to TI's terms and conditions of sale supplied at the time of order acknowledgment. TI warrants performance of its products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are used to the extent TI deems necessary to support this warranty. Except where mandated by government requirements, testing of all parameters of each product is not necessarily performed.

TI assumes no liability for applications assistance or customer product design. Customers are responsible for their products and applications using TI products, software and / or services. To minimize the risks associated with customer products and applications, customers should provide adequate design, testing and operating safeguards.

Any access to and / or use of TI software described in this document is subject to Customers entering into formal license agreements and payment of associated license fees. TI software may solely be used and / or copied subject to and strictly in accordance with all the terms of such license agreements.

Customer acknowledges and agrees that TI products and / or software may be based on or implement industry recognized standards and that certain third parties may claim intellectual property rights therein. The supply of products and / or the licensing of software do not convey a license from TI to any third party intellectual property rights and TI expressly disclaims liability for infringement of third party intellectual property rights.

TI does not warrant or represent that any license, either express or implied, is granted under any TI patent right, copyright, mask work right, or other TI intellectual property right relating to any combination, machine, or process in which TI products, software or services are used.

Information published by TI regarding third-party products, software or services does not constitute a license from TI to use such products, software or services or a warranty, endorsement thereof or statement regarding their availability. Use of such information, products, software or services may require a license from a third party under the patents or other intellectual property of the third party, or a license from TI under the patents or other intellectual property of TI.

No part of this document may be reproduced or transmitted in any form or by any means, electronic or mechanical, including photocopying and recording, for any purpose without the express written permission of TI.

0.1 Export Control Statement

Recipient agrees that it will not knowingly export or re-export, directly or indirectly, any product or technical data (as defined by the U.S, EU and other Export Administration Regulations) including software, or any controlled product restricted by other applicable national regulations, received from Disclosing party under this Agreement, or any direct product of such technology, to any destination to which such export or re-export is restricted or prohibited by U.S or other applicable laws, without obtaining prior authorisation from U.S. Department of Commerce and other competent Government authorities to the extent required by those laws. This provision shall survive termination or expiration of this Agreement.

According to our best knowledge of the state and end-use of this product or technology, and in compliance with the export control regulations of dual-use goods in force in the origin and exporting countries, this

technology is classified as given on the front page.

This product or technology may require export or re-export license for shipping it in compliance with certain countries regulations.

0.2 Document History

Date:	Version:	Status:	Author:	Approved By:
2007-04-11	1.0	Draft	E.N.	
Initial version.				
2006-06-06	1.1		F.C.	
Specification updated according to H.G.J [6]				
2006-09-04	1.2		F.C	
Added section 4 and 5. Tuning sensitivity updated according to H.G.J. [6]				
2006-12-09	1.3		F.C.	
Updated content according to H.G.J feedback.				
2007-04-11	002	Submitted	a0389010	
Updated content with info about stray capacitance. X-tal specification for Cl=14 pF added				
2007-04-25	003	Submitted	a0389010	
Export control added. Submitted for TI internal review				
2007-05-15	004	Submitted	a0389010	
Submitted for Approval. Updated based on Review feedback.				
2007-05-15	005	Approved	Claus Lunde	a0794494
Approved				
2007-05-16	006	Approved	a0389010	a0794494
Important Notice added				
2007-07-30	007	Approved	a0389010	a0794494
X-tal mouting figure added				

0.3 References, Abbreviations, Terms

[1] 3GPP TS 45.005 version 5.9.0 (Release 5)

“Digital cellular telecommunications system (phase 2+); Radio transmission and reception “

[2] 3GPP TS 51.010-1 version 5.5.0 (Release 5)

“Digital cellular telecommunications system (phase 2+); MS conformance specification “

[3] Locosto Radio Interface (lcost_radio_interface, Rev 1.0)

[4] System hardware implementation LOCOSTO and LOCOSTO-LITE (locosto_shi_13_01_00_01796.doc Rev 1.4)

[5] RD329: Leonardo VCXO specification. (RD329.DOC)

[6] H. G. J.: “Locosto_26MHz_Crystal_Specification”

[7] Locosto Electrical Specification v1.8

[8] Locosto Layout Guidelines.

Table of Contents

1	Introduction	5
2	26 MHz crystal specification:	6
2.1	Specification for $C_{load} = 12.5 \text{ pF}$	6
2.2	Specification for $C_{load} = 14 \text{ pF}$	7
2.3	Tuning sensitivity vs. stray capacitance in PCB	8
3	Is the crystal “centred” versus DCXO coarse tuning (CFA)?	9
4	Is the crystal having enough AFC tuning range (FFA)?	11
5	DCXO details	13
5.1	DCXO system description	13
5.2	DCXO core description.....	13
5.3	CFA.....	13
5.4	FFA	14
5.5	Locosto input capacitance.....	15
5.6	Typical voltage swing at crystal	15
A	IMPORTANT NOTICE.....	16

1 Introduction

Purpose of this document is to provide to the Locosto user the 26 MHz requirements for the reference quartz crystal oscillator (XTAL).

This document describes the Locosto 26 MHz crystal specification [3] with following modifications coming from TIDK [6]

- Tuning sensitivity requirement replaces C0 and C1 requirements. This change is intended to make it easier to widen selection of acceptable crystals from different suppliers
- It must be possible to approve the crystals according to the IEC 60444 specification. This is not a requirement but is specified to ensure that the crystal manufactures deliver what is specified.
- Better description of frequency dip, since the original description has been misunderstood several times.
- Requirements for spurious response, shock and vibration tolerance, leak and solderability are added. The requirements come from RD329 [5].
- Requirements for storage temperature and humidity added.

The Locosto DCXO consists of 3 basic blocks. 2 active blocks (Locosto and crystal) and one passive (the PCB).

To achieve desired DCXO performance, it is important to optimize the PCB layout and to select a crystal that matches the requirements. To assist customers, crystal specifications for two different load capacitances are listed in this document, one corresponding to a PCB layout with low capacitance and one with high capacitance.

The Document also gives a DCXO architecture overview and main parameters which may help in the crystal selection and verification.

2 26 MHz crystal specification:

2.1 Specification for $C_{load} = 12.5 \text{ pF}$

Table 1. Specification for crystal with $CL = 12.5 \text{ pF}$

Parameters	Test conditions	Min.	Typ.	Max.	Unit
Nominal Frequency			26		MHz
Frequency tolerance @ CL	at $25^{\circ}\text{C} \pm 3^{\circ}\text{C}$			± 10.0	ppm
Temperature Characteristics	in reference to $+25^{\circ}\text{C}$ over $-20^{\circ}\text{C} \sim +75^{\circ}\text{C}$			± 10.0	ppm
Aging					
1st year				± 1.0	ppm
after 5 years				± 2.5	ppm
Dips vs. temperature (Slope)	$-20^{\circ}\text{C} \sim +75^{\circ}\text{C}$			0.3	ppm/ $^{\circ}\text{C}$
Frequency versus temperature slope at 25°C	at $25^{\circ}\text{C} \pm 7^{\circ}\text{C}$	-0.5		0	ppm/ $^{\circ}\text{C}$
Equivalent Series Resistance				50	Ω
Standard load capacitance (CL)			12.5		pF
Tuning sensitivity @ $CL = 12.5 \text{ pF}$	Tuning sensitivity specification is only valid for a PCB layout where the parasitic stray capacitance is below 1.0 pF .	11.1		18	ppm/pF
Shunt capacitance (C_0)	Tuning sensitivity is primary requirement but Min., Typ. and Max. C_0 must be specified to TI.				pF
Series capacitance (C_1)	Tuning sensitivity is primary requirement but Min., Typ. and Max. C_1 must be specified to TI.				fF
Drive level			50	100	μW
Spurious Ratio ($20\log(R_{sp}/R_1)$)		10			dB
Humidity		20		75	%
Storage temperature		-40		+90	$^{\circ}\text{C}$
Shock test	Test Ea according to IEC 60068-2-27 or similar Test Eb according to IEC 60068-2-29 or similar				
Vibration test	Test Fc according to IEC 60068-2-6 or similar				
Leak test	Test according to IEC 60068-2-17, method 1 and 2 or similar				
Solderability	Test according to IEC 60068-2-54 and IEC 60068-2-69 or similar				

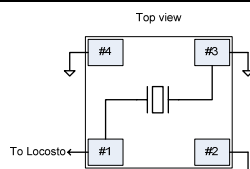


Figure 1. Crystal mounting for specification validation

Crystal testing procedure is left to the discretion of the suppliers, however, it must meet the requirements in Table 1 or Table 2 when tested according to the IEC 60444 test specifications and mounted as shown in Figure 1.

2.2 Specification for $C_{load} = 14 \text{ pF}$

Table 2. Specification for crystal with $CL = 14.0 \text{ pF}$.

Parameters	Test conditions	Min.	Typ.	Max.	Unit
Nominal Frequency			26		MHz
Frequency tolerance @ CL	at $25^{\circ}\text{C} \pm 3^{\circ}\text{C}$			± 10.0	ppm
Temperature Characteristics	in reference to $+25^{\circ}\text{C}$ over $-20^{\circ}\text{C} \sim +75^{\circ}\text{C}$			± 10.0	ppm
Aging					
1st year				± 1.0	ppm
after 5 years				± 2.5	ppm
Dips vs. temperature (Slope)	$-20^{\circ}\text{C} \sim +75^{\circ}\text{C}$			0.3	ppm/ $^{\circ}\text{C}$
Frequency versus temperature slope at 25°C	at $25^{\circ}\text{C} \pm 7^{\circ}\text{C}$	-0.5		0	ppm/ $^{\circ}\text{C}$
Equivalent Series Resistance				50	Ω
Standard load capacitance (CL)			14		pF
Tuning sensitivity @ $CL = 14 \text{ pF}$	Tuning sensitivity specification is only valid for a PCB layout where the parasitic stray capacitance is between 1.0 pF and 2.0 pF .	10.8		15	ppm/pF
Shunt capacitance (C_0)	Tuning sensitivity is primary requirement but Min., Typ. and Max. C_0 must be specified to TI.				pF
Series capacitance (C_1)	Tuning sensitivity is primary requirement but Min., Typ. and Max. C_1 must be specified to TI.				fF
Drive level			50	100	μW
Spurious Ratio ($20\log(R_{sp}/R_1)$)		10			dB
Humidity		20		75	%
Storage temperature		-40		+90	$^{\circ}\text{C}$
Shock test	Test Ea according to IEC 60068-2-27 or similar Test Eb according to IEC 60068-2-29 or similar				
Vibration test	Test Fc according to IEC 60068-2-6 or similar				
Leak test	Test according to IEC 60068-2-17, method 1 and 2 or similar				
Solderability	Test according to IEC 60068-2-54 and IEC 60068-2-69 or similar				

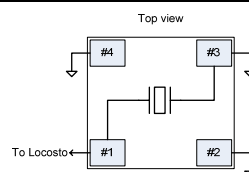


Figure 2. Crystal mounting for specification validation

Crystal testing procedure is left to the discretion of the suppliers, however, it must meet the requirements in Table 1 or Table 2 when tested according to the IEC 60444 test specifications and mounted as shown in Figure 2

2.3 Tuning sensitivity vs. stray capacitance in PCB.

The curves in Figure 3 and Figure 4 below show the dependence of the crystal tuning sensitivity on the stray capacitance of the PCB. If the stray capacitance is above 1 pF the crystal specification for the tuning sensitivity has to be modified to fulfil the tuning requirements. Also change of both C_{load} and the tuning sensitivity is a possibility.

Figure 3. Tuning sensitivity requirements vs. stray capacitance. $C_l = 12.5$ pF

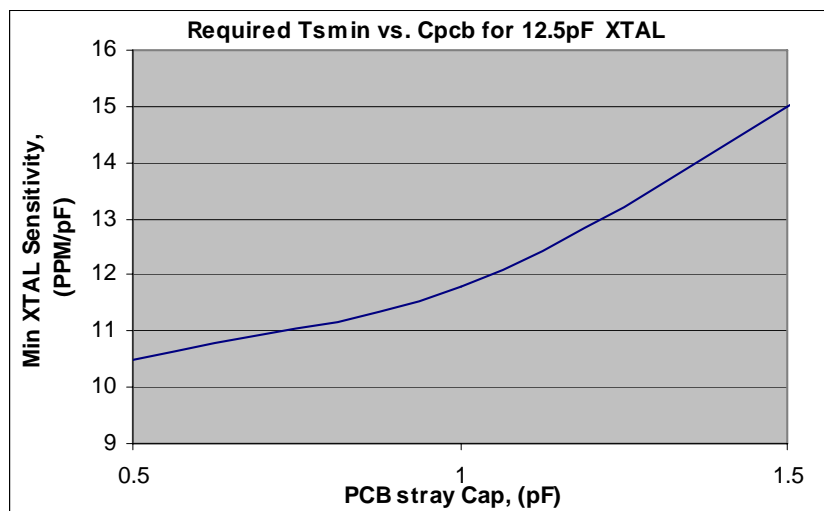
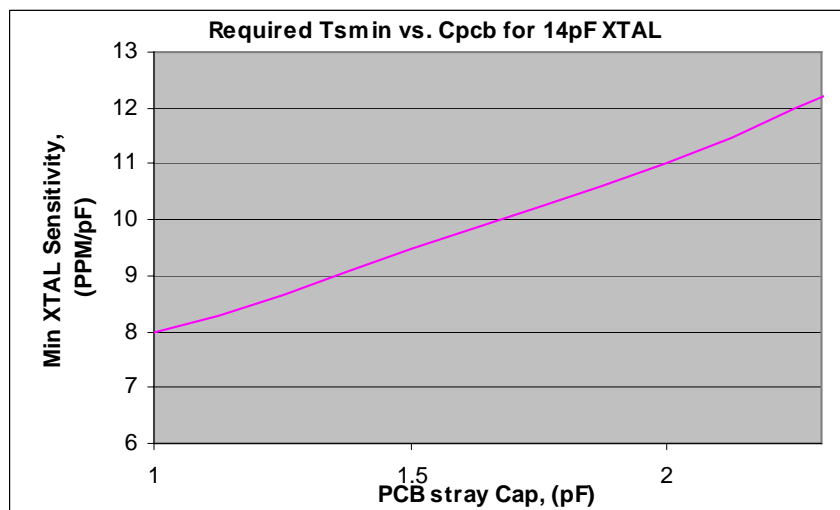


Figure 4. Tuning sensitivity requirements vs. stray capacitance. $C_l = 14.0$ pF



From Figure 3 it can be seen, that the stray capacitance in the actual used PCB must be below 1 pF to be able to use the crystal specification from section 2.1 regarding tuning sensitivity.

If it is not possible to keep the stray capacitance in the layout below 1 pF the alternative specification from section 2.2 is to be used to secure the expected performance and secure CFA calibration.

3 Is the crystal “centred” versus DCXO coarse tuning (CFA)?

In order to evaluate if the crystal is centred versus DCXO coarse tuning (CFA word), the frequency deviation versus CFA code (coarse tuning) has to be characterized. This can be done using ETM commands.

The following test equipment is needed for performing this characterization:

- A laptop or stationary PC with a RS-232 or USB interface for running the ETM SW on target.
- A Base Station Simulator (BSS), (e.g. R&S CMU200).
- A calibrated power supply.
- Misc. cables and level converters for interfacing to Mobile Station (MS).

The characterization includes the following steps

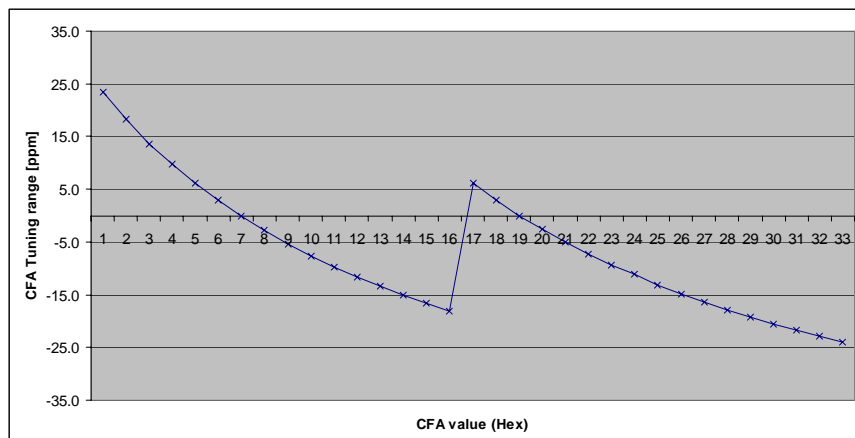
1. The MS is set up to transmit at channel 40 at power level 15
2. The frequency error of the carrier is measured with a BSS
3. The needed parameters are calculated and changed

ETM Procedure:

```
tms 1 (enter in test mode)
rfpw 7 6 0 (select GSM-900 band)
rfpw 2 40 (select TCH 40)
rfpw 8 0 (disable AFC)
rfpw 9 0 (set AFC at middle range)
txpw 1 15 (select TX power to power level 15)
rfe 3 (do both RX and TX on TCH without network sync)
mw -2 0xFFFF1E4C 0x0001 (write the CFA value into the target)
<measure the frequency deviation on the BSS
mw -2 0xFFFF1E4C 0x0081 (add 0x80 to CFA value, see section 5.3)
<measure the frequency deviation on the BSS
mw -2 0xFFFF1E4C 0x0101 (add 0x80 to CFA value)
<measure the frequency deviation on the BSS
...
<measure the frequency deviation on the BSS
mw -2 0xFFFF1E4C 0x0FFD (add 0x80 to CFA value)
<measure the frequency deviation on the BSS
```

The typical result should be similar to the one illustrated in Figure 5.

Figure 5. CFA tuning range validation



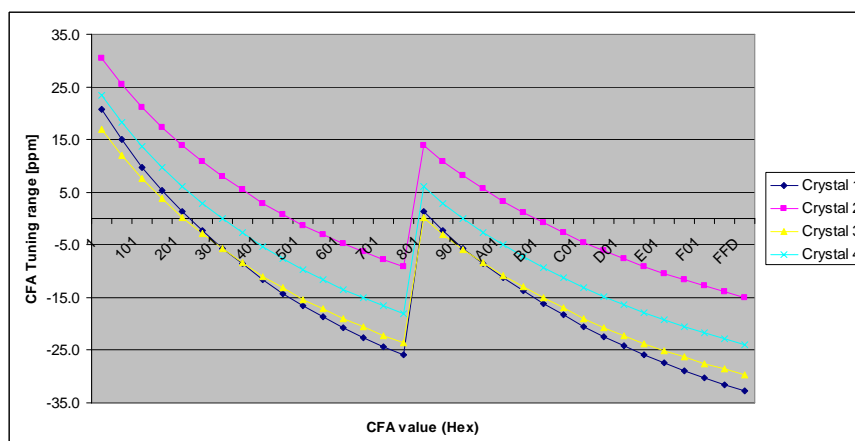
The discontinuity in the middle of the graph occurs because of CFA tuning range extension capacitor. The two subranges, on the left and on the right side of Figure 5 show partial overlap, and for some values of coarse frequency adjustment CFA values from either left sub-range or from the right sub-range may be chosen.

In order to see if the selected crystal is centred over the CFA range, max and min deviation have to be similar. Of course it is expected that in production crystals will exhibit some deviation from being perfectly centred. This is perfectly normal, providing crystal frequency tolerance specified in Table 1 or Table 2 is met. CFA calibration will be used to compensate this frequency tolerance during in-phone calibration.

When CFA tuning range is measured with a perfectly centred (0 ppm tolerance) crystal, at least ± 20 ppm of CFA tuning range is required, in order to compensate for the allowed frequency tolerance of the crystal plus DCXO tolerances in Locosto as well as variations of the stray capacitance tolerances in the PCB.

Nevertheless the range has to be limited from 0x0001 to 0x0F80 for in-phone production calibration. When the DCXO coarse tuning calibration is not working properly (example is no signal provide at Locosto input during CFA calibration) then 0x0F81 CFA code is reported which is a potential code that could also be valid after a correct calibration. Failing calibration codes greater than 0x0F80 removes this potential issue.

Figure 6. Example of crystal selection:



In this example, crystal 4 would give the best fit, with symmetrical CFA tuning range of ± 22 ppm and it could be selected as a reference example against which all other crystals should be compared.

4 Is the crystal having enough AFC tuning range (FFA)?

In order to evaluate if the selected crystal is having enough AFC tuning range after CFA calibration, the frequency deviation versus FFA code (Fine Frequency Adjustment) has to be characterized. This can be done using ETM commands.

The following test equipment is needed for performing this characterization:

- A laptop or stationary PC with a RS-232 or USB interface for running the ETM SW on target.
- A Base Station Simulator (BSS),(e.g. R&S CMU200).
- A calibrated power supply.
- Misc. cables and level converters for interfacing to Mobile Station (MS).

The characterization includes the following steps

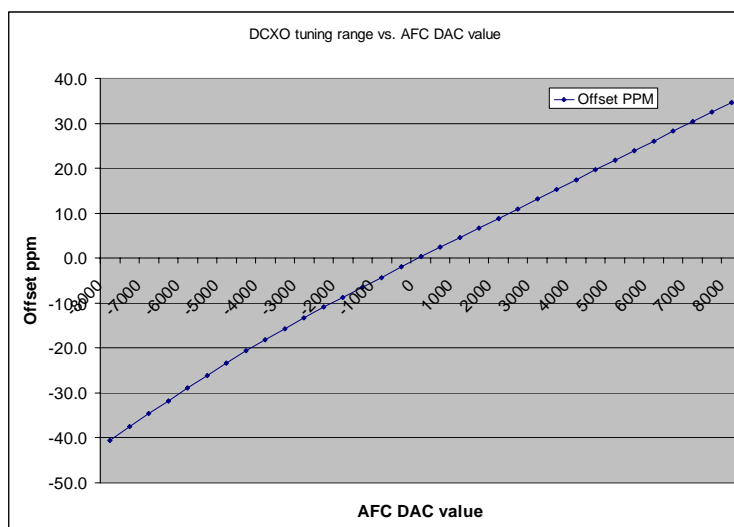
1. The MS is set up to transmit at channel 40 at power level 15
2. The frequency error of the carrier is measured with a BSS
3. The needed parameters are calculated and changed

ETM Procedure:

```
tms 1 (enter in test mode)
rfpw 7 6 0 (select gsm900 band)
rfpw 2 40 (select TCH 40)
rfpw 8 0 (disable AFC)
rfpw 9 -8000 (set AFC at lower range value)
txpw 1 15 (select TX power to power level 15)
rfe 3 (do both RX and TX on TCH without network sync)
<measure the frequency deviation on the BSS
rfpw 9 -7500 (AFC value is increased in step of 500)
<measure the frequency deviation on the BSS
rfpw 9 -7000 (AFC value is increased in step of 500)
<measure the frequency deviation on the BSS
...
<measure the frequency deviation on the BSS
rfpw 9 8000 (AFC value is set to higher range value)
<measure the frequency deviation on the BSS
```

Calculate the measured values into ppm deviation.

Figure 7. AFC tuning range vs. AFC DAC value



The requirement for any design will be to have an AFC tuning range $> \pm 21$ ppm to secure proper tuning range for temperature, aging

The selected crystal in Figure 7 does full fill this requirement with a tuning range of more than ± 35 ppm.

5 DCXO details

5.1 DCXO system description

The DCXO system consists of an external crystal, DCXO core based on Colpitts oscillator, a switchable capacitor array, amplitude control loop and a current DAC. It also includes an autonomous digital startup system to control the startup sequence of the band-gap reference and the LDO voltage regulator for the DCXO that is based on a 32 KHz clock. It is also used to ensure reliable start-up of the DCXO itself. An ADC inside the block is used as part of the amplitude control loop.

5.2 DCXO core description

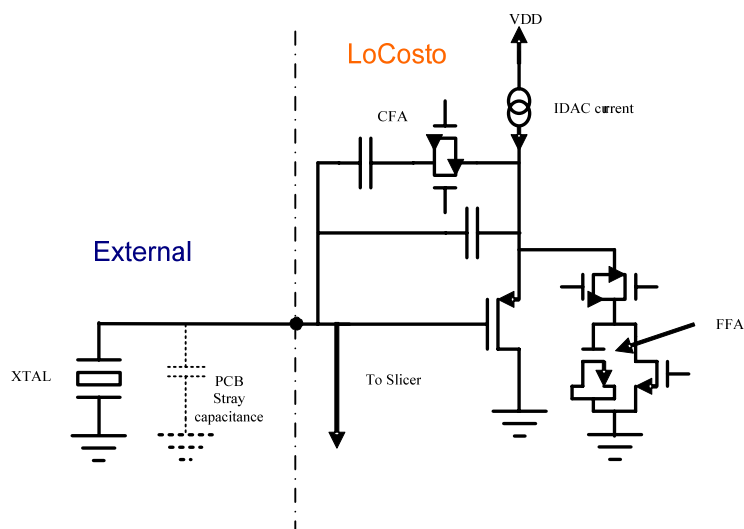
DCXO (Digitally Controlled Crystal Oscillator) is a digitally tuneable crystal oscillator centred at 26MHz for GSM applications. Both the amplitude and the frequency of oscillation are digitally controllable. Figure 8 here below shows a simplified top level schematic of DCXO core schematic.

Colpitts style oscillator is chosen for pin savings, with only one crystal connection pin required besides VDDX and VSSX.

Coarse frequency adjustment (CFA) is controlled through 10 bit digital control word. Frequency change is accomplished by altering the feedback capacitor.

AFC fine frequency control (also called FFA “Fine Frequency adjustment”) is controlled through a 14-bit capacitor array. Frequency change is accomplished by altering the source-to-ground capacitance.

Figure 8. DCXO equivalent diagram



5.3 CFA

Coarse Frequency Adjustment (CFA) capacitor consists of modified-binary array with 10-bit control, with individual weights of 1, 2, 3, 6, 12, 24, 48, 96, 192 corresponding to bits 0 through 8 respectively and a special sub-ranging capacitor of ~144 units controlled by the MSB bit (bit 9) of the CFA word.

CFA word can be read at register CTL_LDO_DCXO at address: 0xFFFF1E4C.

Bits <15:12> => not used

Bits <11:2> => Capacitor non-binary weighted: 144,192,96,48,24,12,6,3,2,1

Bit <1:0> => reserved (internal use)

Example: 0FD1=[~~0000~~ 1111 1101 ~~0001~~] = 144+192+96+48+24+12+0+3+0+0 = 519 unit caps

The range of CFA capacitor array is the following:

$$CFA = CFA_{min} + CFA_{step} * CFA_{code}$$

Where: $CFA_{min}=7pF$, $CFA_{step}=31fF$ and $0 \leq CFA_{code} \leq 583$

Note: These numbers are simulated values given by design team.

5.4 FFA

The Fine Frequency Adjustment is controlled through a 14-bit capacitor array with a segmented tapered capacitor array which effectively linearize the transfer function. The top 10bits are thermometer coded and the lower 4 LSBs are Sigma Delta (1st order) modulated. A memory array like architecture is used to facilitate the layout.

The range of FFA capacitor array is the following:

$$FFA = FFA_{min} + FFA_{step} * FFA_{code}$$

Where: $FFA_{min}=10pF$, $FFA_{step}=3.7fF$ and $0 \leq FFA_{code} \leq 2^{14}-1$

Note: These numbers are simulated values given by design team

As FFA is typical covering +/-25ppm, the average slope is typically 0.003ppm/LSB

(Tuning range/ number of bits=50ppm/ 2^{14} ~0.003ppm/LSB)

This is not aligned with frequency resolution as extracted from “Locosto Electrical specification” v1p6

Parameters	Test conditions	Symbol	Min. 2	Min. 1	Typ.	Max. 1	Max. 2	Unit
Center Frequency			-	-	26	-	-	MHz
Frequency error before calibration			-50	-	-	-	+50	ppm
Dynamic range	After calibration		-20/+20					ppm
Frequency resolution	Step to step		0	-	0.03	-	+0.05	ppm/LSB
Number of control bits					14			bits

As mentioned in test condition column, this item is not related to the average slope of the FFA but to the maximum FFA step to step frequency deviation.

(Step to step resolution = $\Delta F / 1 \text{ LSB}$ [ppm/LSB] where ΔF is frequency deviation in ppm between FFA value and FFA value + 1 LSB)

The FFA has a monotonic response but all steps do not provide equivalent frequency deviation. Several steps will have minor frequency deviation and then next step will have like 0.03ppm frequency deviation. Average

slope will still show 0.003ppm/LSB slope and overall system frequency accuracy does not suffer from this FFA response.

5.5 Locosto input capacitance

Locosto input capacitance can be estimated as follow:

$$C_{\text{input}} = 1 / (1/CFA + 1/FFA) + Cpara$$

Where: Cpara is the Locosto internal parasitic capacitor to ground and can be estimated as 2pF (It does not include any PCB parasitic capacitor)

5.6 Typical voltage swing at crystal

Locosto typical voltage swing at crystal is 0.45 Volt peak.

A IMPORTANT NOTICE

Texas Instruments Incorporated and its subsidiaries (TI) reserve the right to make corrections, modifications, enhancements, improvements, and other changes to its products and services at any time and to discontinue any product or service without notice. Customers should obtain the latest relevant information before placing orders and should verify that such information is current and complete. All products are sold subject to TI's terms and conditions of sale supplied at the time of order acknowledgment.

TI warrants performance of its hardware products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are used to the extent TI deems necessary to support this warranty. Except where mandated by government requirements, testing of all parameters of each product is not necessarily performed.

TI assumes no liability for applications assistance or customer product design. Customers are responsible for their products and applications using TI components. To minimize the risks associated with customer products and applications, customers should provide adequate design and operating safeguards.

TI does not warrant or represent that any license, either express or implied, is granted under any TI patent right, copyright, mask work right, or other TI intellectual property right relating to any combination, machine, or process in which TI products or services are used. Information published by TI regarding third-party products or services does not constitute a license from TI to use such products or services or a warranty or endorsement thereof. Use of such information may require a license from a third party under the patents or other intellectual property of the third party, or a license from TI under the patents or other intellectual property of TI.

Reproduction of information in TI data books or data sheets is permissible only if reproduction is without alteration and is accompanied by all associated warranties, conditions, limitations, and notices. Reproduction of this information with alteration is an unfair and deceptive business practice. TI is not responsible or liable for such altered documentation.

Resale of TI products or services with statements different from or beyond the parameters stated by TI for that product or service voids all express and any implied warranties for the associated TI product or service and is an unfair and deceptive business practice. TI is not responsible or liable for any such statements.

TI products are not authorized for use in safety-critical applications (such as life support) where a failure of the TI product would reasonably be expected to cause severe personal injury or death, unless officers of the parties have executed an agreement specifically governing such use. Buyers represent that they have all necessary expertise in the safety and regulatory ramifications of their applications, and acknowledge and agree that they are solely responsible for all legal, regulatory and safety-related requirements concerning their products and any use of TI products in such safety-critical applications, notwithstanding any applications-related information or support that may be provided by TI. Further, Buyers must fully indemnify TI and its representatives against any damages arising out of the use of TI products in such safety-critical applications.

TI products are neither designed nor intended for use in military/aerospace applications or environments unless the TI products are specifically designated by TI as military-grade or "enhanced plastic." Only products designated by TI as military-grade meet military specifications. Buyers acknowledge and agree that any such use of TI products which TI has not designated as military-grade is solely at the Buyer's risk, and that they are solely responsible for compliance with all legal and regulatory requirements in connection with such use.

TI products are neither designed nor intended for use in automotive applications or environments unless the specific TI products are designated by TI as compliant with ISO/TS 16949 requirements. Buyers acknowledge and agree that, if they use any non-designated products in automotive applications, TI will not be responsible for any failure to meet such requirements.

Following are URLs where you can obtain information on other Texas Instruments products and application solutions:

Products		Applications	
Amplifiers	amplifier.ti.com	Audio	www.ti.com/audio
Data Converters	dataconverter.ti.com	Automotive	www.ti.com/automotive
DSP	dsp.ti.com	Broadband	www.ti.com/broadband
Interface	interface.ti.com	Digital Control	www.ti.com/digitalcontrol
Logic	logic.ti.com	Military	www.ti.com/military
Power Mgmt	power.ti.com	Optical Networking	www.ti.com/opticalnetwork
Microcontrollers	microcontroller.ti.com	Security	www.ti.com/security
RFID	www.ti-rfid.com	Telephony	www.ti.com/telephony
Low Power Wireless	www.ti.com/lpw	Video & Imaging	www.ti.com/video
		Wireless	www.ti.com/wireless

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265
Copyright © 2007, Texas Instruments Incorporated